

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Stefan Schulte et al.

Application No.: 10/743,792

Filing Date:

December 24, 2003

Group Art Unit: 2877

Examiner: Unassigned

Confirmation No.: 6170

Title: INTERFEROMETER SYSTEM, METHOD FOR RECORDING AN INTERFEROGRAM AND METHOD

FOR PROVIDING AND MANUFACTURING AN OBJECT HAVING A TARGET SURFACE

FIRST INFORMATION DISCLOSURE STATEMENT TRANSMITTAL LETTER

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

	,		
Sir:			
РТО	Enclosed is a	FIRST identified pate	Information Disclosure Statement and accompanying form ent application.
	☐ The fee of \$180 ☐ A statement uning \$1.17(p) are aligned Charge ☐ A check in the aigned Charge ☐ Ch	0.00 (1806) as der 37 C.F.R. der 37 C.F.R. so enclosed to Dependent of to cre	ion of an IDS is required. s set forth in 37 C.F.R. § 1.17(p) is also enclosed. § 1.97(e) is also enclosed. § 1.97(e), and the fee of \$180.00 (1806) as set forth in 37 C.F.R. osit Account No. 02-4800 for the fee due is enclosed for the fee due. edit card. Form PTO-2038 is attached.
		d by this paper	to charge any appropriate fees under 37 C.F.R. §§ 1.16, 1.17 and r, and to credit any overpayment, to Deposit Account No. 02-4800.
			Respectfully submitted,
			BURNS, DOANE, SWECKER & MATHIS, L.L.P.
Alex	. Box 1404 andria, Virginia 2231) 836-6620	3-1404	By Foogles H. Pearson
Date	s: June 4 2004		Douglas H. Pearson Registration No. 47 851



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FIRST INFORMATION DISCLOSURE STATEMENT

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Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, the accompanying information is being submitted in accordance with 37 C.F.R. §§ 1.97 and 1.98.

Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed. However, copies of the listed U.S. patents and U.S. patent application publications are not enclosed since it is no longer required according to the July 11, 2003 waiver of the requirement for copies of cited U.S. patents and U.S. patent application publications in national patent applications filed after June 30, 2003 and international applications entering the national stage under 35 U.S.C. § 371 after June 30, 2003.

The documents are being submitted within three (3) months of the filing or entry of the national stage of this application or before the first Office Action on the merits, whichever is later. Since these documents are being filed within the time period set forth in 37 C.F.R. § 1.97(b), no fee or statement is required.

FIRST Information Disclosure Statement
Application No. 10/743,792
Attorney's Docket No. 007413-070
Page 2

To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

DE 41 19 744 A1 is a foreign-language document. The undersigned has been informed that the document corresponds to U.S. Patent No. 5,343,294, which is listed on the attached PTO-1449 Form.

Also enclosed is an International Search Report mailed on October 1, 2002, in connection with the parent application PCT/EP02/07080. Also enclosed is a search report from the German Patent Office dated April 30, 2002, received in connection with corresponding German Patent Application No. 10130902.3.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

Date <u>June 4, 2004</u>

Douglas H. Pearson Registration No. 47,851

P.O. Box 1404 Alexandria, Virginia 22313-1404 (703) 836-6620



Sheet

Substitute for form 1449A/PTO & 1449B/PTO

FIRST INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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1 Of

Com	plete if Known	
Application Number	10/743,792	
Filing Date	December 24, 2003	JUN 0 4 2004
First Named Inventor	Stefan Schulte et al.	E
Examiner Name	Unassigned	To some
Attorney Docket Number	007413-070	W. Mar

	U.S. PATENT DOCUMENTS				
Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)	
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Examiner	Date
Signature	Considered

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



Sheet

Substitute for form 1449A/PTO & 1449B/PTO

FIRST INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many	sheets	as necessary)	
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Examiner Name	Unassigned
Attorney Docket Number	007413-070

NON-PATENT LITERATURE DOCUMENTS			
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
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Examiner Signature	Date Considered		